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#### **Features**

- 0805 1.1mm SMD LED
- High Brightness
- AllnGaP / InGaN Technology
- Small package
- High reliability
- Clear Lens

## **Applications**

- Consumer Electronics
- Wearables
- Automobile After Market
- Industrial Equipment

## **Description**

The IN-S85DATRG is a dual color 0805 package with versatile design capabilities. It is a PCB type LED which can be used in various applications.

### **Recommended Solder Pattern**

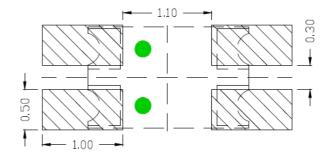


Figure 1. IN-S85DATRG Solder Pattern

## Package Dimensions in mm

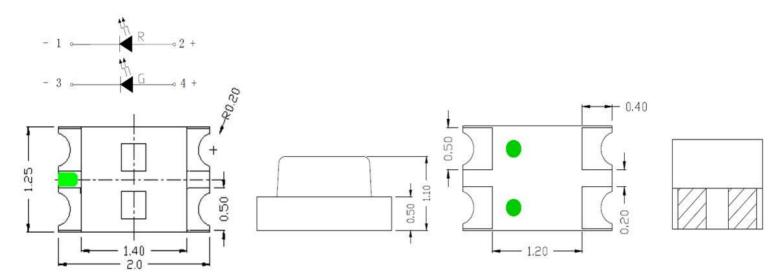


Figure 2. IN-S85DATRG Package Dimensions



## Absolute Maximum Rating at 25°C (Note 1)

Product	Emission Color	P <sub>d</sub> (mW)	I <sub>F</sub> (mA)	I <sub>FP</sub> * (mA)	V <sub>R</sub> (V)	Top (°C)	T <sub>ST</sub> (°C)	
	Red	75	25	70				
IN-S85DATRG	Green	75	25	100	5	-30°C~+85°C	-40°C~+90°C	

#### Notes

1. Condition for IFP is pulse of 1/10 duty and 0.1msec width

#### **ESD Precaution**

ATTENTION: Electrostatic Discharge (ESD) protection



The symbol above denotes that ESD precaution is needed. ESD protection for GaP and AlGaAs based chips is necessary even though they are relatively safe in the presence of low static-electric discharge. Parts built with AllnGaP, GaN, or/and InGaN based chips are STATIC SENSITIVE devices. ESD precaution must be taken during design and assembly. If manual work or processing is needed, please ensure the device is adequately protected from ESD during the process.

Please be advised that normal static precautions should be taken in the handling and assembly of this device to prevent damage or degradation which may be induced by electrostatic discharge (ESD).

## Electrical Characteristics T<sub>A</sub> = 25C (Note 1)

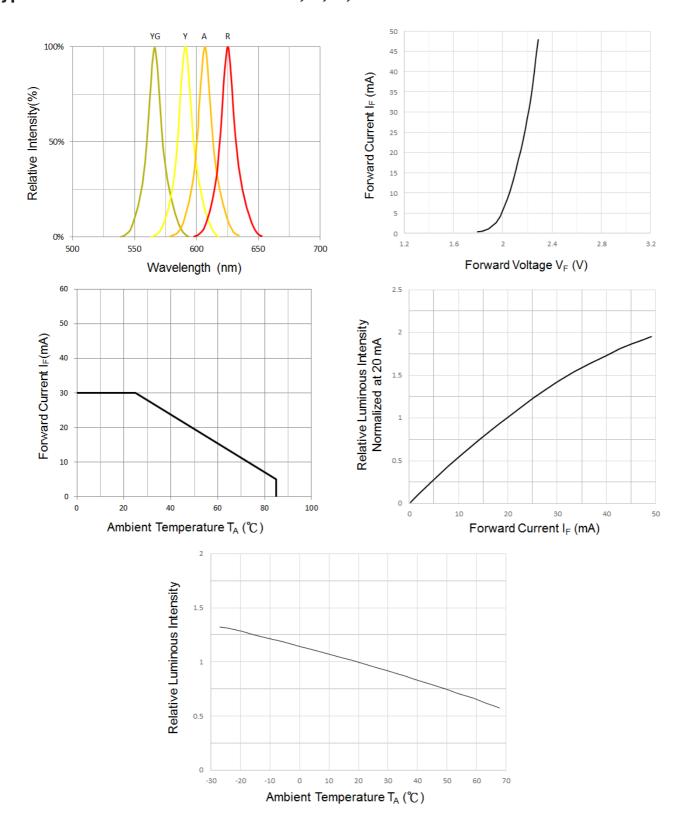
Dodg	Emission		V <sub>F</sub> (	(V)		λ(nm)		Viewing Angel	I* <sub>V</sub> (mcd)
Product	Color	I <sub>F</sub> (mA)	typ.	max	<b>λ</b> D	<b>λ</b> P	Δλ	<b>2</b> <i>\theta</i> 1/2	typ.
IN COEDATEC	Red	20	2.2	2.6	622	630	17	120	140
IN-S85DATRG	Green	20	3.2	3.6	522	530	30	120	450

#### **Notes**

1. Performance guaranteed only under conditions listed in above tables.

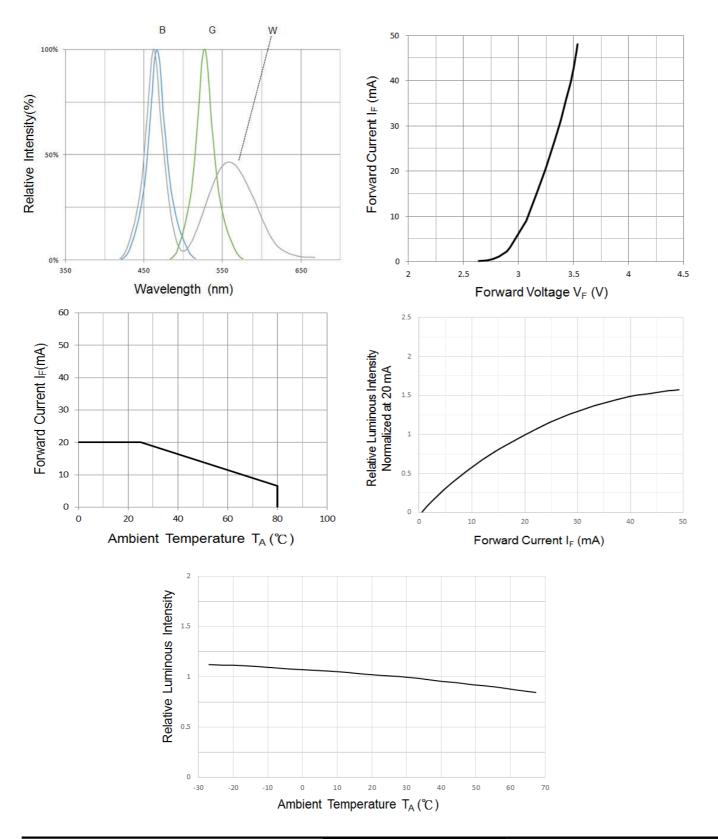


# Typical Characteristic Curves – YG, Y, A, R



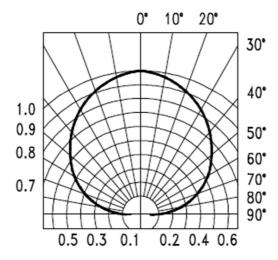


# Typical Characteristic Curves - B, G, W





## **Typical Characteristic Curves – Radiation Pattern**

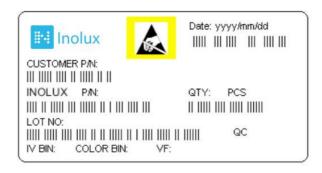


## **Ordering Information**

Product	Emission Color	Test Current I <sub>F</sub> (mA)	Luminous Intensity I <sub>V</sub> (mcd) (Typ.)	Forward Voltage V <sub>F</sub> (V) (Typ.)	Orderable Part Number
IN-S85DATRG	Red	20	140	2.2	IN-S85DATRG
IN-SOSDATAG	Green	20	450	3.2	IN-303DATHG



## **Label Specifications**



## Inolux P/N:

I	N	-	S	8	5	D	Α	Т			R	G		-	Х	Х	Х	Χ
			Material	Pac	kage	Varia	ation	Orientation	Current	Lens	Co	olor	Chip Type			stor am <sub>l</sub>		
	olux ⁄ID		S = PCB Type	85DA	= 2.0 x	1.25 x 1	.1mm	T = Top Mount	(Blank) = 20mA	(Blank) = Clear		30nm 30nm	(blank) = Standard					

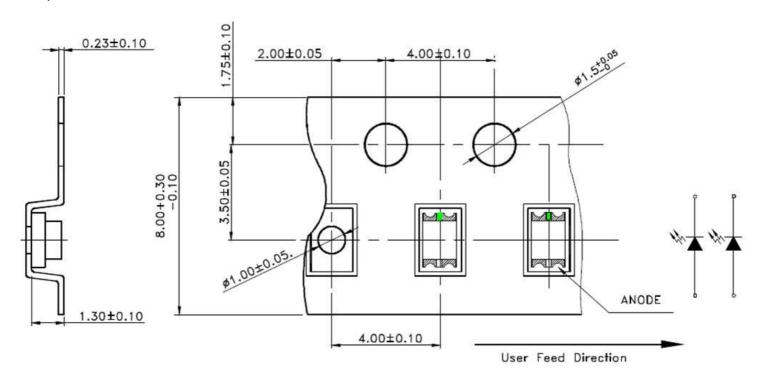
#### Lot No.:

Z	2	0	1	7	01	24	001
Internal		Voor (2017	2019	Month	Data	Corial	
Tracker		fear (2017	, 2018,)	Month	Date	Serial	

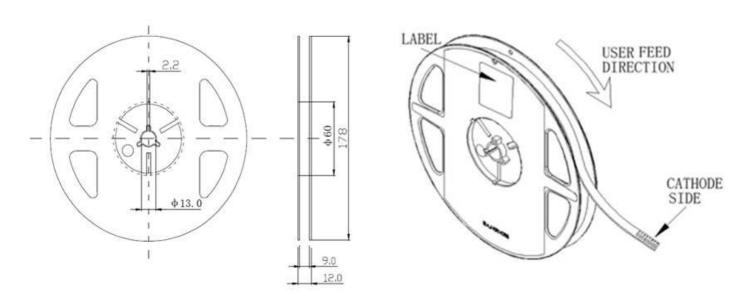


## Packaging Information: 3000pcs Per Reel

# Tape Dimension

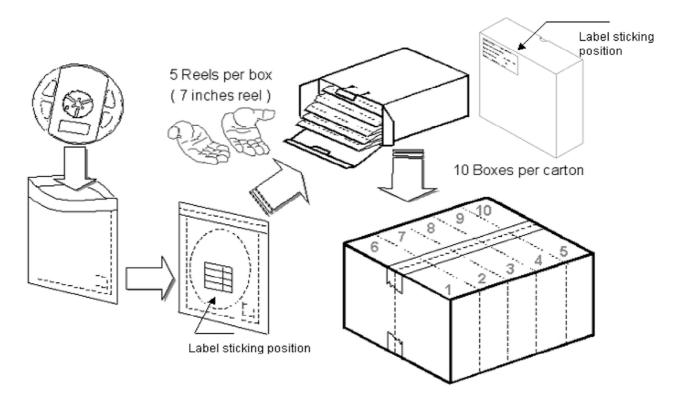


## **Reel Dimension**





## **Packing Dimension**



5 boxes per carton are available depending on shipment quantity.

Specification	Material	Quantity
Per EIA 481-1A specs	Conductive black tape	3000pcs per reel
Per EIA 481-1A specs	Conductive black	
IN standard	Paper	
220x240mm	Aluminum laminated bag/ no-zipper	One reel per bag
IN standard	Paper	Non-specified
	Per EIA 481-1A specs Per EIA 481-1A specs IN standard 220x240mm	Per EIA 481-1A specs Conductive black tape Per EIA 481-1A specs Conductive black IN standard Paper 220x240mm Aluminum laminated bag/ no-zipper

#### Others:

Each immediate box consists of 5 reels. The 5 reels may not necessarily have the same lot number or the same bin combinations of Iv,  $\lambda_D$  and Vf. Each reel has a label identifying its specification; the immediate box consists of a product label as well.

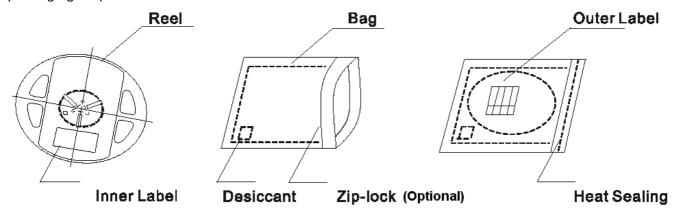


## **Dry Pack**

All SMD optical devices are **MOISTURE SENSITIVE**. Avoid exposure to moisture at all times during transportation or storage. Every reel is packaged in a moisture protected anti-static bag. Each bag is properly sealed prior to shipment.

Upon request, a humidity indicator will be included in the moisture protected anti-static bag prior to shipment.

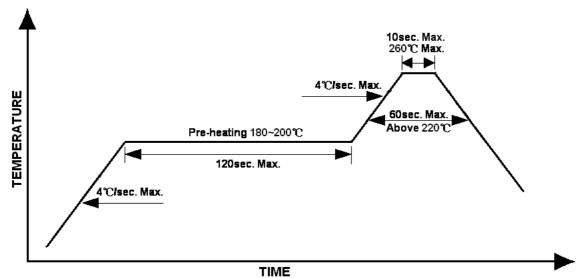
The packaging sequence is as follows:



## **Reflow Soldering**

- Recommended tin glue specifications: melting temperature in the range of 178~192 °C
- The recommended reflow soldering profile is as follows (temperatures indicated are as measured on the surface of the LED resin):







#### **Precautions**

- Avoid exposure to moisture at all times during transportation or storage.
- Anti-Static precaution must be taken when handling GaN, InGaN, and AllnGaP products.
- It is suggested to connect the unit with a current limiting resistor of the proper size. Avoid applying a reverse voltage.
- Avoid operation beyond the limits as specified by the absolute maximum ratings.
- Avoid direct contact with the surface through which the LED emits light.
- If possible, assemble the unit in a clean room or dust-free environment.

## Reworking

- Rework should be completed within 5 seconds under 260 °C.
- The iron tip must not come in contact with the copper foil.
- Twin-head type is preferred.

## Cleaning

Following are cleaning procedures after soldering:

- An alcohol-based solvent such as isopropyl alcohol (IPA) is recommended.
- Temperature x Time should be 50°C x 30sec. or <30°C x 3min
- Ultra sonic cleaning: < 15W/ bath; bath volume ≤ 1liter
- Curing: 100 °C max, <3min

#### **Cautions of Pick and Place**

- Avoid stress on the resin at elevated temperature.
- Avoid rubbing or scraping the resin by any object.
- Electro-static may cause damage to the component. Please ensure that the equipment is properly grounded. Use of an ionizer fan is recommended.





Reliability

Temperature bias   Temperature bias   Temperature bias   Temperature cycle	enability			
Tailuries   Heterence   For all reliability   monitoring tests according to JEDEC Level 2   JSTD-020   JESD2-B102-B   Accelerated aging 155°C/ 60% R.H. for 168hrs   Accelerated aging 155°C/ 24hrs   Tinning speed: 2.5+0.5cm/s   Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s   Dipping soldering terminal only soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s   Dipping soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s   Dipping soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s   Dipping soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s   Dipping soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350°C/ 60% R.H. for 168hrs   2.) Tamb25°C; IF=20mA; duration 1000hrs   Tamb25°C; IF=20mA; duration 1000hrs   Tamb25°C; IF=20mA; duration 1000hrs   Duration: 1000hrs   Tamb25°C, IF=20mA, Duration: 1000hrs   Duration: 1000hrs   Tamb25°C, IF=20mA, Duration: 1000hrs   Duration: 1000hrs   Duration: 1000hrs   Duration: 1000hrs   Tamb25°C, IF=20mA, Ip=100mA, Duty   Cycle=0.125 (tp=125 (tp	ltem			Conditions
Precondition   monitoring tests according to JEDEC Level 2   2   Moisture storage at 85°C/ 60% R.H. for 168hrs   1Q/ 1/ 22/ 0   JESD22-B102-B   Accelerated aging 155°C/ 24hrs   Tinning speed: 2.5+0.5cm/s   Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s   Tinning: A: 215°C/ 2+1s   Ti	item			
To JEDEC Level 2			J-STD-020	
Solderability	Precondition			
Solderability		to JEDEC Level 2		168hrs
Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s		1Q/ 1/ 22/ 0	JESD22-B102-B	Accelerated aging 155℃/ 24hrs
CNS-5067   Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s	Solderability		And CNS-5068	Tinning speed: 2.5+0.5cm/s
Resistance to soldering heat   Soldering bath temperature   A: 260+/-5℃; 10+/-1s   B: 350+/-10℃; 3+/-0.5s     1Q/ 1/ 40/ 0				
Soldering heat   A: 260+/-5°C; 10+/-1s     B: 350+/-10°C; 3+/-0.5s     CNS-11829   1.) Precondition: 85°C bakin g for 24hrs     85°C / 60%R.H. for 168hrs     2.) Tamb25°C; IF=20mA; duration 1000hrs     High humidity, high temperature bias   1Q/ 1/ 45/ 0     High temperature bias   1Q/ 1/ 20     High temperature bias   1Q/ 1/ 40/ 0     Pulse life test   1Q/ 1/ 40/ 0     Tamb: 55°C     High temperature bias   1Q/ 1/ 40/ 0     Tamb: 55°C     High temperature bias     1Q/ 1/ 76/ 0     JESD-A104-A     IEC 68-2-14, Nb     High humidity     1Q/ 1/ 40/ 0     High humidity     1Q/ 1/ 40/ 0     CNS-6117     1Q/ 1/ 40/ 0     Soldering in the set of t			CNS-5067	
B: 350+/-10°C; 3+/-0.5s				
Operating life test         1Q/ 1/ 40/ 0         CNS-11829         1.) Precondition: 85℃ bakin g for 24hrs 85℃/ 60%R.H. for 168hrs 2.) Tamb25℃; IF=20mA; duration 1000hrs           High humidity, high temperature bias         1Q/ 1/ 45/ 0         JESD-A101-B         Tamb: 85℃ Humidity: 85% R.H., IF=5mA Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55℃ IF=20mA Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         Tamb25℃, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μs,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb IEC 69+3℃ 2 chamber/ Air-to-air type           High humidity storage test         1Q/ 1/ 40/ 0         CNS-6117         60+3℃ 90+5/-10% R.H. for 500hrs           High temperature storage test         1Q/ 1/ 40/ 0         CNS-554         100+10℃ for 500hrs           Low temperature         1Q/ 1/ 40/ 0         CNS-6118         -40+5℃ for 500hrs	soldering heat			
Operating life test         85℃/60%R.H. for 168hrs 2.) Tamb25℃; IF=20mA; duration 1000hrs           High humidity, high temperature bias         1Q/1/45/0           High temperature bias         IN specs.           Tamb: 55℃ Humidity: 85% R.H., IF=5mA Duration: 1000hrs           High temperature bias         IQ/1/20           High temperature bias         IQ/1/40/0           Tamb: 55℃ IF=20mA Duration: 1000hrs           Tamb25℃, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μs, T=1sec) Duration 500hrs)           Temperature cycle         IQ/1/76/0           JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type           High humidity storage test         IQ/1/40/0         CNS-6117         60+3℃ 90+5/-10% R.H. for 500hrs           High temperature storage test         IQ/1/40/0         CNS-554         100+10℃ for 500hrs           Low temperature         IQ/1/40/0         CNS-6118         -40+5℃ for 500hrs				
2.) Tamb25℃; IF=20mA; duration 1000hrs		1Q/ 1/ 40/ 0	CNS-11829	
High humidity, high temperature bias         1Q/ 1/ 45/ 0         JESD-A101-B         Tamb: 85℃ Humidity: 85% R.H., IF=5mA Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55℃ IF=20mA Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         Tamb25℃, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min. 300 cycles 2 chamber/ Air-to-air type           High humidity storage test         1Q/ 1/ 40/ 0         CNS-6117         60+3℃ 90+5/-10% R.H. for 500hrs           High temperature storage test         1Q/ 1/ 40/ 0         CNS-554         100+10℃ for 500hrs           Low temperature         1Q/ 1/ 40/ 0         CNS-6118         -40+5℃ for 500hrs	Operating life test			85℃/ 60%R.H. for 168hrs
high temperature bias         Humidity: 85% R.H., IF=5mA Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55℃ IF=20mA Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         Tamb25℃, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μs,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type           High humidity storage test         1Q/ 1/ 40/ 0         CNS-6117         60+3℃ 90+5/-10% R.H. for 500hrs           High temperature storage test         1Q/ 1/ 40/ 0         CNS-554         100+10℃ for 500hrs           Low temperature         1Q/ 1/ 40/ 0         CNS-6118         -40+5℃ for 500hrs				2.) Tamb25℃; IF=20mA; duration 1000hrs
bias         Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55℃ IF=20mA Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         Tamb25℃, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type           High humidity storage test         1Q/ 1/ 40/ 0         CNS-6117         60+3℃ 90+5/-10% R.H. for 500hrs           High temperature storage test         1Q/ 1/ 40/ 0         CNS-554         100+10℃ for 500hrs           Low temperature         1Q/ 1/ 40/ 0         CNS-6118         -40+5℃ for 500hrs	High humidity,	1Q/ 1/ 45/ 0	JESD-A101-B	Tamb: 85℃
High temperature bias   1Q/ 1/ 20   IN specs.   Tamb: 55℃   IF=20mA   Duration: 1000hrs    Pulse life test   1Q/ 1/ 40/ 0   Tamb25℃, If=20mA, Ip=100mA, Duty   cycle=0.125 (tp=125 μ s,T=1sec)   Duration 500hrs    Temperature cycle   1Q/ 1/ 76/ 0   JESD-A104-A   A cycle: -40 degree C 15min; +85 degree C   15min   Thermal steady within 5 min   300 cycles   2 chamber/ Air-to-air type    High humidity   1Q/ 1/ 40/ 0   CNS-6117   60+3℃   90+5/-10% R.H. for 500hrs    High temperature storage test   1Q/ 1/ 40/ 0   CNS-554   100+10℃ for 500hrs    Low temperature   1Q/ 1/ 40/ 0   CNS-6118   -40+5℃ for 500hrs	high temperature			Humidity: 85% R.H., IF=5mA
High temperature bias	bias			Duration: 1000hrs
bias       IP=20HA Duration: 1000hrs         Pulse life test       1Q/ 1/ 40/ 0       Tamb25℃, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)         Temperature cycle       1Q/ 1/ 76/ 0       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type         High humidity storage test       1Q/ 1/ 40/ 0       CNS-6117       60+3℃ 90+5/-10% R.H. for 500hrs         High temperature storage test       1Q/ 1/ 40/ 0       CNS-554       100+10℃ for 500hrs         Low temperature       1Q/ 1/ 40/ 0       CNS-6118       -40+5℃ for 500hrs	High tomporature	1Q/ 1/ 20	IN specs.	Tamb: 55℃
Pulse life test				IF=20mA
Pulse life test $ \begin{array}{c} \text{Cycle=0.125 } \ (\text{tp=125} \ \mu  \text{s,T=1sec}) \\ \text{Duration 500hrs}) \\ \text{Temperature} \\ \text{cycle} \\ \end{array} \begin{array}{c} 1\text{Q/ 1/ 76/ 0} \\ \text{Temperature} \\ \text{cycle} \\ \end{array} \begin{array}{c} 1\text{Q/ 1/ 76/ 0} \\ \text{Temperature} \\ \text{cycle} \\ \end{array} \begin{array}{c} 1\text{Q/ 1/ 76/ 0} \\ \text{IEC 68-2-14, Nb} \\ \end{array} \begin{array}{c} \text{JESD-A104-A} \\ \text{IEC 68-2-14, Nb} \\ \text{IS min} \\ \text{Thermal steady within 5 min} \\ 300 \ \text{cycles} \\ 2 \ \text{chamber/ Air-to-air type} \\ \end{array} \\ \text{High humidity} \\ \text{storage test} \\ \text{High temperature} \\ \text{High temperature} \\ \text{Storage test} \\ \end{array} \begin{array}{c} 1\text{Q/ 1/ 40/ 0} \\ \text{CNS-554} \\ \end{array} \begin{array}{c} \text{CNS-6118} \\ \text{CNS-6118} \\ \end{array} \begin{array}{c} \text{CNS-500hrs} \\ \text{CNS-500hrs} \\ \end{array}$	bias			Duration: 1000hrs
Duration 500hrs)  1Q/ 1/ 76/ 0  Temperature cycle  High humidity storage test  High temperature attrage test  Low temperature  1Q/ 1/ 40/ 0  Duration 500hrs)  A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type  CNS-6117  60+3℃ 90+5/-10% R.H. for 500hrs  1Q/ 1/ 40/ 0  CNS-554  100+10℃ for 500hrs		1Q/ 1/ 40/ 0		Tamb25℃, If=20mA,, Ip=100mA, Duty
Temperature cycle       1Q/ 1/ 76/ 0       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min; +85 degree C 15min         High humidity storage test       1Q/ 1/ 40/ 0       CNS-6117       60+3℃ 90+5/-10% R.H. for 500hrs         High temperature storage test       1Q/ 1/ 40/ 0       CNS-554       100+10℃ for 500hrs         Low temperature       1Q/ 1/ 40/ 0       CNS-6118       -40+5℃ for 500hrs	Pulse life test			cycle=0.125 (tp=125 μ s,T=1sec)
Temperature cycle				Duration 500hrs)
Temperature cycle		1Q/ 1/ 76/ 0	JESD-A104-A	A cycle: -40 degree C 15min; +85 degree C
cycle       Infermal steady within 5 min         300 cycles       2 chamber/ Air-to-air type         High humidity       1Q/ 1/ 40/ 0         Storage test       CNS-6117         High temperature       1Q/ 1/ 40/ 0         CNS-554       100+10℃ for 500hrs         Low temperature       1Q/ 1/ 40/ 0         CNS-6118       -40+5℃ for 500hrs	T t		IEC 68-2-14, Nb	
300 cycles   2 chamber/ Air-to-air type	•		,	Thermal steady within 5 min
High humidity storage test $1Q/1/40/0$ CNS-6117 $60+3$ °C         High temperature storage test $1Q/1/40/0$ CNS-554 $100+10$ °C for 500hrs         Low temperature $1Q/1/40/0$ CNS-6118 $-40+5$ °C for 500hrs	cycle			
High humidity storage test $1Q/1/40/0$ CNS-6117 $60+3$ °C         High temperature storage test $1Q/1/40/0$ CNS-554 $100+10$ °C for 500hrs         Low temperature $1Q/1/40/0$ CNS-6118 $-40+5$ °C for 500hrs				2 chamber/ Air-to-air type
storage test         90+5/-10% R.H. for 500hrs           High temperature storage test         1Q/ 1/ 40/ 0           CNS-554         100+10℃ for 500hrs           1Q/ 1/ 40/ 0         CNS-6118           -40+5℃ for 500hrs	High humidity	1Q/ 1/ 40/ 0	CNS-6117	
High temperature storage test $1Q/1/40/0$ CNS-554 $100+10$ °C for 500hrsLow temperature $1Q/1/40/0$ CNS-6118 $-40+5$ °C for 500hrs				90+5/-10% R.H. for 500hrs
storage test   CNS-6118   -40+5°C for 500hrs	High temperature	1Q/ 1/ 40/ 0	CNS-554	100+10℃ for 500hrs
Low temperature         1Q/ 1/ 40/ 0         CNS-6118         -40+5℃ for 500hrs				
·		1Q/ 1/ 40/ 0	CNS-6118	-40+5℃ for 500hrs
	storage test			



# IN-S85DATRG Top View SMD LED 0805 PCB Type

**Revision History** 

Changes since last revision	Page	Version No.	Revision Date
Initial Release		V1.0	05-12-2017

#### **DISCLAIMER**

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- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- 2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.